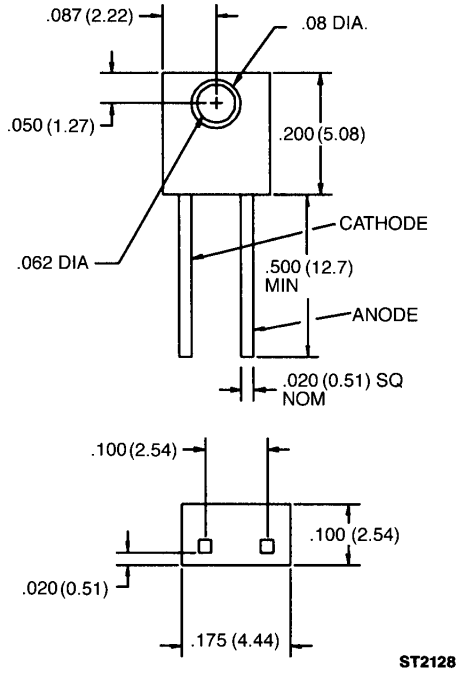
OPTOELECTRONICS

GaAs INFRARED EMITTING DIODE

QEE113

PACKAGE DIMENSIONS



NOTES:
1. DIMENSIONS ARE IN INCHES (mm).
2. TOLERANCE IS ±.010 (.25)
   UNLESS OTHERWISE SPECIFIED.

DESCRIPTION

The QEE113 is a 940 nm GaAs LED encapsulated in a wide angle, orange, plastic sidelooker shell package.

FEATURES

- Tight production E_e distribution with min/max limits.
- Steel lead frames for improved reliability in solder mounting.
- Good optical-to-mechanical alignment.
- Mechanically and wavelength matched to QSE11X series phototransistor.
- Plastic package color allows easy recognition from phototransistor.
- High irradiance level.

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ABSOLUTE MAXIMUM RATINGS (T_A = 25°C Unless Otherwise Specified)

Storage Temperature	−40°C to + 100°C
Operating Temperature	−40°C to + 100°C
Soldering:	
Lead Temperature (Iron)	240°C for 5 sec. [2,3,4,5]
Lead Temperature (Flow)	260°C for 10 sec. [2,3,5]
Continuous Forward Current	50 mA
Reverse Voltage	5.0 Volts
Power Dissipation	100 mW[1]

ELECTRICAL CHARACTERISTICS (T_A = 25°C Unless Otherwise Specified)
(All measurements made under pulse conditions.)

PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITIONS
Forward Voltage	V_F	—		1.50	V	I_F = 20 mA
Reverse Leakage Current	I_R	—		10	μA	V_R = 5.0 V
Peak Emission Wavelength	λ_P	—	940	—	nm	I_F = 20 mA
Emission Angle at ½ Power	θ	—	±25	—	Degrees	
Radiant Incidence	E_θ	0.015			mW/10° Cone	I_F = 20 mA[6,7]

NOTES

1. *Derate power dissipation linearly 1.33 mW/°C above 25°C.*
2. *RMA flux is recommended.*
3. *Methanol or Isopropyl alcohols are recommended as cleaning agents.*
4. *Soldering iron tip 1/16" (1.6 mm) minimum from housing.*
5. *As long as leads are not under any stress or spring tension.*
6. *Measurement is taken at the end of a single 100 μsec pulse.*
7. *E_θ is a measurement of the average apertured radiant energy incident upon a sensing area 0.444" (11.3 mm) in diameter, perpendicular to and centered on the mechanical axis of the lens, and 2.54" (64.4 mm) from the measurement surface. E_θ is not necessarily uniform within the measurement area.*